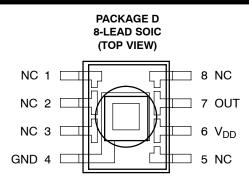


TAOS050K - OCTOBER 2007

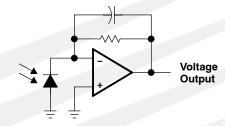
- Monolithic Silicon IC Containing Photodiode, Operational Amplifier, and Feedback Components
- Converts Light Intensity to a Voltage
- High Irradiance Responsivity, Typically
 - 64 mV/(μ W/cm²) at λ_p = 640 nm (TSL250RD)
 - 58 mV/(μ W/cm²) at λ_p = 940 nm (TSL260RD)
- Single Voltage Supply Operation
- Low Dark (Offset) Voltage . . . 10 mV Max
- Low Supply Current . . . 1.1 mA Typical
- Wide Supply-Voltage Range . . . 2.7 V to 5.5 V
- Low-Profile Surface-Mount Package:
 - Clear Plastic for TSL250RD and TSL251RD
 - Visible Light-Cutoff Filter Plastic for TSL260RD and TSL261RD
- Lead (Pb) Free and RoHS Compliant Package



Description

The TSL250RD, TSL251RD, TSL260RD, and TSL261RD are light-to-voltage optical sensors, each combining a photodiode and a transimpedance amplifier on a single monolithic IC. The TSL250RD and TSL260RD have an equivalent feedback resistance of 16 M Ω and a photodiode measuring 1 square mm. The TSL251RD and TSL261RD have an equivalent feedback resistance of 8 M Ω and a photodiode measuring 0.5 square mm. Output voltage is directly proportional to the light intensity (irradiance) on the photodiode. These devices have improved amplifier offset-voltage stability and low power consumption.

Functional Block Diagram



Terminal Functions

TERMINAL		DECORPTION
NAME	NO.	DESCRIPTION
GND	4	Ground (substrate). All voltages are referenced to GND.
OUT	7	Output voltage.
V_{DD}	6	Supply voltage.

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1

TAOS050K - OCTOBER 2007

Absolute Maximum Ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V _{DD} (see Note 1)	6 \
Output current, IO	
Duration of short-circuit current at (or below) 25°C (see Note 2)	5 9
Operating free-air temperature range, TA	25°C to 85°C
Storage temperature range, T _{stq}	
Solder conditions in accordance with JEDEC J-STD-020A, maximum temperature (s	see Note 3) 260°C

- NOTES: 1. All voltages are with respect to GND.
 - 2. Output may be shorted to supply.
 - 3. The device may be hand soldered provided that heat is applied only to the solder pad and no contact is made between the tip of the solder iron and the device lead. The maximum time heat should be applied to the device is 5 seconds.

Recommended Operating Conditions

	MIN	NOM MAX	UNIT
Supply voltage, V _{DD}	2.7	5.5	V
Operating free-air temperature, T _A	0	70	°C

Electrical Characteristics at V_{DD} = 5 V, T_A = 25°C, R_L = 10 k Ω (unless otherwise noted) (see Notes 3, 4, 5, and 6)

			λp = 640 nm					λ p = 940 nm							
PARAMETER		TEST CONDITIONS	TSL250RD			TSL251RD			TSL260RD			TSL261RD			UNIT
		CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
V_D	Dark voltage	E _e = 0	0	5	10	0	5	10	0	5	10	0	5	10	mV
V _{OM}	Maximum output voltage	V _{DD} = 4.5 V	3	3.3		3	3.3		3	3.3		3	3.3		V
	Output voltage	$E_e = 31 \mu W/cm^2$	1.5	2	2.5										V
.,		$E_e = 124 \mu W/cm^2$				1.5	2	2.5							
Vo		$E_e = 34 \mu W/cm^2$							1	2	3				V
		$E_e = 132 \mu\text{W/cm}^2$										1	2	3	
R _e	Irradiance responsivity	See Note 7		64			16			58			15		mV/ (μW/ cm ²)
	erature	at of $T_A = 0^{\circ}C$ to $70^{\circ}C$		2			2			8			8		mV/°C
	icient of it voltage (V _O)			0.1			0.1			0.4			0.4		%/°C
		$E_e = 31 \mu W/cm^2$		1.1	1.7										
	Supply	$E_e = 124 \ \mu W/cm^2$					1.1	1.7							_
I _{DD}	current	$E_e = 34 \mu W/cm^2$								1.1	1.7				mA
		E_e = 132 μ W/cm ²											1.1	1.7	

NOTES: 4. Measurements are made with R_L = 10 $k\Omega$ between output and ground.

- 5. Optical measurements are made using small-angle incident radiation from an LED optical source.
- 6. The 640 nm input irradiance E_e is supplied by an AlInGaP LED with peak wavelength λ_p = 640 nm.
- 7. The 940 nm input irradiance E_e is supplied by a GaAs LED with peak wavelength λ_p = 940 nm.
- 8. Irradiance responsivity is characterized over the range $V_O = V_D$ to 3 V. The best-fit straight line of Output Voltage V_O versus irradiance E_e over this range will typically have a positive extrapolated V_O value for $E_e = 0$.
- The temperature coefficient of output voltage measurement is made by adjusting irradiance such that V_O is approximately 2 V at 25°C and then with irradiance held constant, measuring V_O while varying the temperature between 0°C and 70°C.

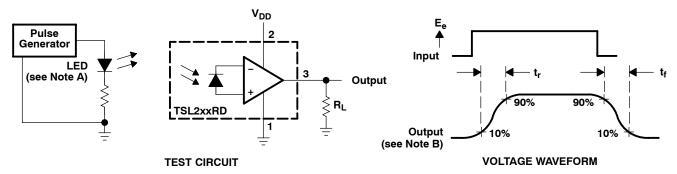


[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

Dvna	mic Characteristics at	$V_{DD} = 5 \text{ V. } T_{\Lambda} = 25$	5° C. $R_1 = 10 \text{ k}\Omega$ ((unless otherwise noted)	(see Figure 1)
_,		• • • • • • • •	,	(41.11000 041.101.11100 110404)	1000 : .90.0 : /

PARAMETER			λ p = 640 nm							λp = 940 nm					
		TEST CONDITIONS	TSL250RD			TSL251RD			T	SL260R	D	TSL261RD			UNIT
		CONDITIONS	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX	
t _r	Output pulse rise time	V _{O(peak)} = 2 V		260			70			260			70		μs
t _f	Output pulse fall time	V _{O(peak)} = 2 V		260			70			260			70		μS
V _n	Output noise voltage	E _e = 0, f = 1000 Hz		0.8			0.7			0.8			0.7		μV/ (√(Hz))

PARAMETER MEASUREMENT INFORMATION

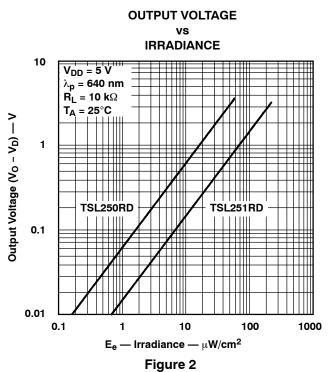


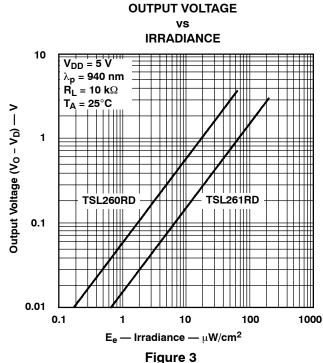
NOTES: A. The input irradiance is supplied by a pulsed light-emitting diode with $t_r < 1 \mu s$, $t_f < 1 \mu s$.

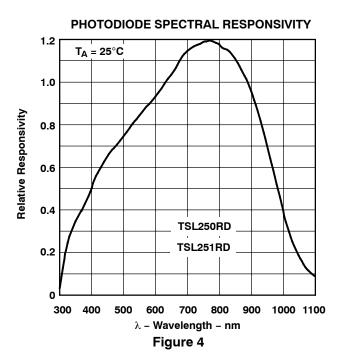
B. The output waveform is monitored on an oscilloscope with the following characteristics: $t_r < 100 \text{ ns}, Z_i \ge 1 \text{ M}\Omega, C_i \le 20 \text{ pF}.$

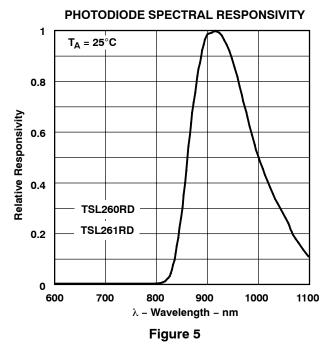
Figure 1. Switching Times

TYPICAL CHARACTERISTICS

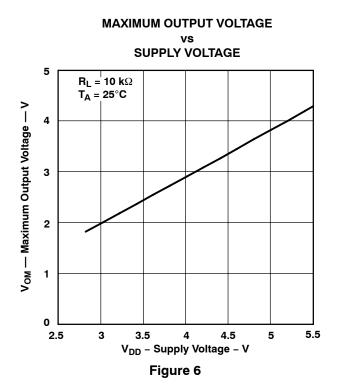


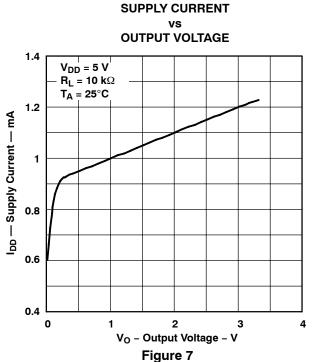




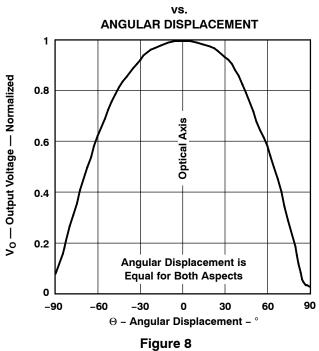


TYPICAL CHARACTERISTICS





NORMALIZED OUTPUT VOLTAGE



TAOS050K - OCTOBER 2007

APPLICATION INFORMATION

Power Supply Considerations

For optimum device performance, power-supply lines should be decoupled by a 0.01- μF to 0.1- μF capacitor with short leads connected between VDD and GND mounted close to the device package.

Device Operational Details

The voltage developed at the output pin (OUT) is given by:

$$V_O = V_D + (R_e) (E_e)$$

where:

V_O is the output voltage

 V_D is the output voltage for dark condition ($E_e = 0$)

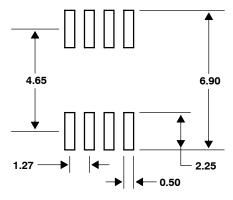
 R_e is the device responsivity for a given wavelength of light given in mV/(μ W/cm²)

 E_e is the incident irradiance in $\mu W/cm^2$

 V_D is a fixed offset voltage resulting primarily from the input offset voltage of the internal op amp. As shown in the equation above, this voltage represents a constant, light-independent term in the total output voltage V_D . At low light levels, this offset voltage can be a significant percentage of V_D . For optimum performance of any given device over the full output range, the value of V_D should be measured (in the absence of light) and later subtracted from all subsequent light measurements (see Figures 2 and 3).

PCB Pad Layout

Suggested PCB pad layout guidelines for the D package is shown in Figure 9.



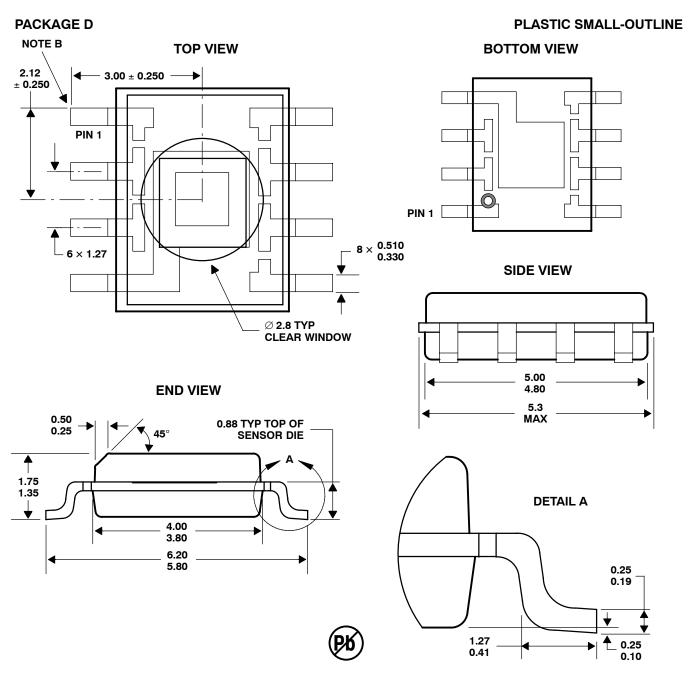
NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

Figure 9. Suggested D Package PCB Layout

MECHANICAL DATA

This SOIC package consists of an integrated circuit mounted on a lead frame and encapsulated with an electrically nonconductive clear plastic compound. The photodiode area is typically 1.02 mm² for the TSL250RD and TSL260RD, and is typically 0.514 mm² for the TSL251RD and TSL261RD.

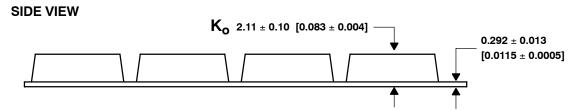


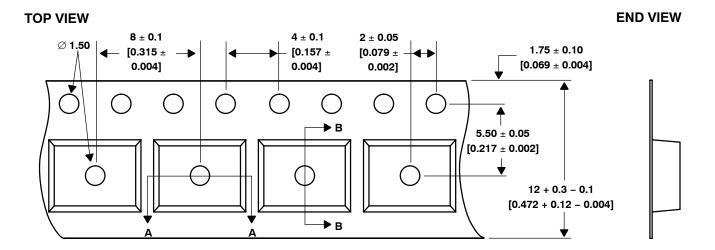
- NOTES: A. All linear dimensions are in millimeters.
 - B. The center of the photo-active area is referenced to the upper left corner tip of the lead frame (Pin 1).
 - C. Package is molded with an electrically nonconductive clear plastic compound having an index of refraction of 1.55.
 - D. This drawing is subject to change without notice.

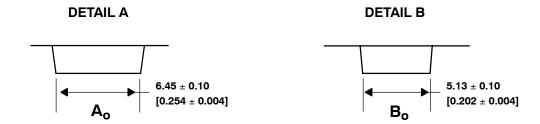
Figure 10. Package D — Plastic Small Outline IC Packaging Configuration



MECHANICAL DATA







NOTES: A. All linear dimensions are in millimeters [inches].

- B. The dimensions on this drawing are for illustrative purposes only. Dimensions of an actual carrier may vary slightly.
- C. Symbols on drawing A_o, B_o, and K_o are defined in ANSI EIA Standard 481-B 2001.
- D. Each reel is 178 millimeters in diameter and contains 1000 parts.
- E. TAOS packaging tape and reel conform to the requirements of EIA Standard 481-B.
- F. This drawing is subject to change without notice.

Figure 11. Package D Carrier Tape

Max -5°C/sec

MANUFACTURING INFORMATION

The Plastic Small Outline IC package (D) has been tested and has demonstrated an ability to be reflow soldered to a PCB substrate.

The solder reflow profile describes the expected maximum heat exposure of components during the solder reflow process of product on a PCB. Temperature is measured on top of component. The component should be limited to a maximum of three passes through this solder reflow profile.

PARAMETER REFERENCE TSL2xxRD 2.5°C/sec Average temperature gradient in preheating Soak time 2 to 3 minutes t_{soak} Time above 217°C Max 60 sec t_1 Time above 230°C Max 50 sec t_2 Time above Tpeak -10°C Max 10 sec t_3 260° C (-0°C/+5°C) Peak temperature in reflow Tpeak

Table 1. TSL2xxRD Solder Reflow Profile

Temperature gradient in cooling

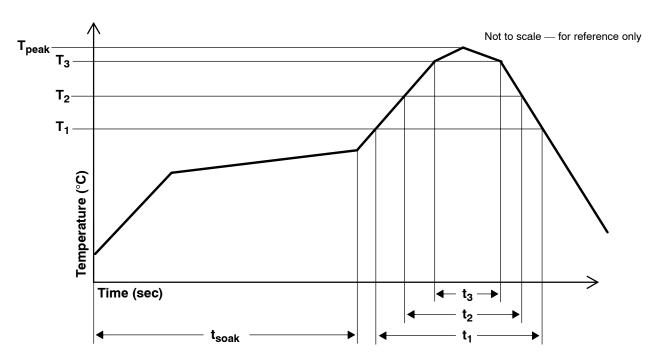


Figure 12. TSL2xxRD Solder Reflow Profile Graph

TAOS050K - OCTOBER 2007

Moisture Sensitivity

Optical characteristics of the device can be adversely affected during the soldering process by the release and vaporization of moisture that has been previously absorbed into the package molding compound. To prevent these adverse conditions, all devices shipped in carrier tape have been pre-baked and shipped in a sealed moisture-barrier bag. No further action is necessary if these devices are processed through solder reflow within 24 hours of the seal being broken on the moisture-barrier bag.

However, for all devices shipped in tubes or if the seal on the moisture barrier bag has been broken for 24 hours or longer, it is recommended that the following procedures be used to ensure the package molding compound contains the smallest amount of absorbed moisture possible.

For devices shipped in tubes:

- 1. Remove devices from tubes
- 2. Bake devices for 4 hours, at 90°C
- 3. After cooling, load devices back into tubes
- 4. Perform solder reflow within 24 hours after bake

Bake only a quantity of devices that can be processed through solder reflow in 24 hours. Devices can be re-baked for 4 hours, at 90°C for a cumulative total of 12 hours (3 bakes for 4 hours at 90°C).

For devices shipped in carrier tape:

- 1. Bake devices for 4 hours, at 90°C in the tape
- 2. Perform solder reflow within 24 hours after bake

Bake only a quantity of devices that can be processed through solder reflow in 24 hours. Devices can be re-baked for 4 hours in tape, at 90°C for a cumulative total of 12 hours (3 bakes for 4 hours at 90°C).



TAOS050K - OCTOBER 2007

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TAOS050K - OCTOBER 2007

